



## **Test Setup Photos-FCC**

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<b>Address of Applicant:</b>	No. 192 Liangjing Rd., Pudong New Area, Shanghai 201303, P.R. China
<b>Equipment Under Test (EUT):</b>	
<b>Product Name:</b>	MCIMX8M-EVK
<b>Model No.:</b>	MCIMX8M-EVK



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## **2 EQUIPMENT UNDER TEST PICTURES**

### **2.1 Radiated Emission Test Setup**

Below 30MHz



30MHz to 1GHz



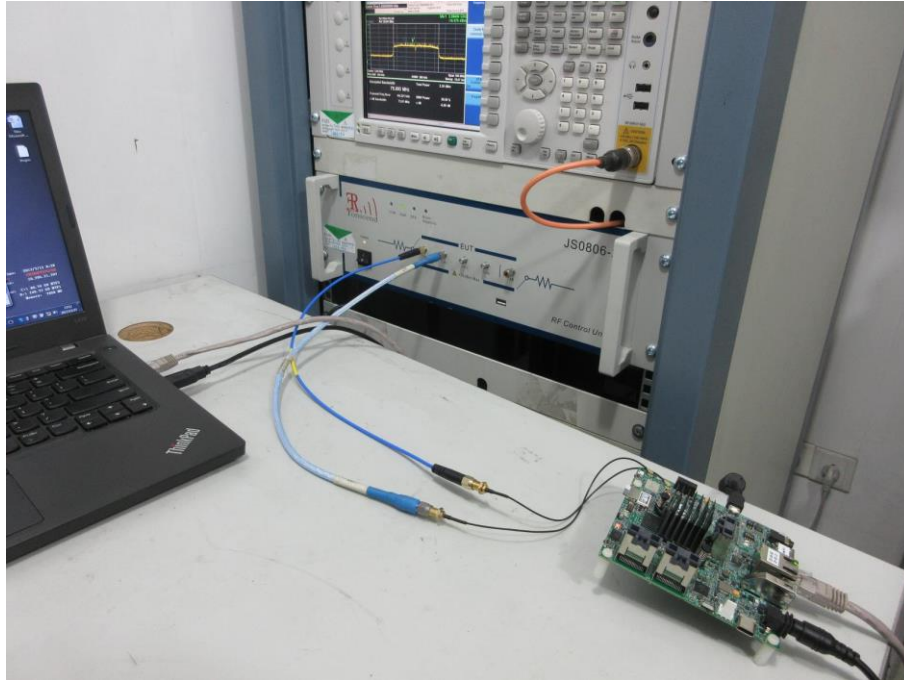
Above 1GHz



## 2.2 RF Conducted Emissions



### 2.3 RF Conducted test



**End**